

P-Channel 1.5-V (G-S) MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A) ^e	Q _g (Typ.)
- 8	0.036 at V _{GS} = - 4.5 V	- 6	14 nC
	0.045 at V _{GS} = - 2.5 V	- 6	
	0.056 at V _{GS} = - 1.8 V	- 6	
	0.077 at V _{GS} = - 1.5 V	- 6	

FEATURES

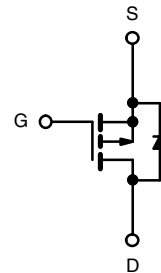
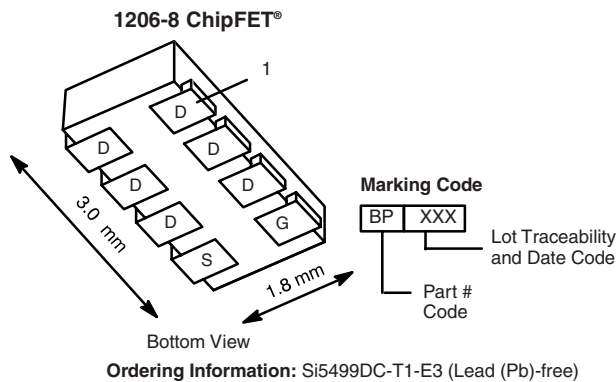
- TrenchFET[®] Power MOSFET: 1.5 V Rated
- Ultra-Low On-Resistance



RoHS
COMPLIANT

APPLICATIONS

- Load Switch for Portable Devices
 - Guaranteed Operation at V_{GS} = 1.5 V Critical for Optimized Design and Longer Battery Life



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 8	V
Gate-Source Voltage	V _{GS}	± 5	
Continuous Drain Current (T _J = 150 °C) ^{a, b}	I _D	T _C = 25 °C	- 6 ^e
		T _C = 70 °C	- 6 ^e
		T _A = 25 °C	- 6 ^{a, b, e}
		T _A = 70 °C	- 5.6 ^{a, b}
Pulsed Drain Current (10 μs Pulse Width)	I _{DM}	- 25	A
Continuous Source-Drain Diode Current ^{a, b}	I _S	T _C = 25 °C	
		T _A = 25 °C	- 2.1 ^{a, b}
Maximum Power Dissipation ^{a, b}	P _D	T _C = 25 °C	6.2
		T _C = 70 °C	4
		T _A = 25 °C	2.5 ^{a, b}
		T _A = 70 °C	1.6 ^{a, b}
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature) ^{c, d}		260	

Notes:

- Surface Mounted on 1" x 1" FR4 board.
- t = 5 s.
- See Solder Profile (<http://www.vishay.com/ppg?73257>). The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- Package limited.


THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, b}	$t \leq 5$ s	R_{thJA}	48	50	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	20	

Notes:

a. Surface Mounted on 1" x 1" FR4 Board.

b. Maximum under Steady State conditions is 95 °C/W.

SPECIFICATIONS $T_J = 25$ °C, unless otherwise noted

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0$ V, $I_D = -250$ μ A	- 8			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250$ μ A		6		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		2.3			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250$ μ A	- 0.35		- 0.8	V
		$V_{DS} = V_{GS}$, $I_D = -5$ mA		- 0.55		
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0$ V, $V_{GS} = \pm 5$ V			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -8$ V, $V_{GS} = 0$ V			- 1	μ A
		$V_{DS} = -8$ V, $V_{GS} = 0$ V, $T_J = 55$ °C			- 10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq 5$ V, $V_{GS} = -4.5$ V	- 25			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = -4.5$ V, $I_D = -5.1$ A		0.030	0.036	Ω
		$V_{GS} = -2.5$ V, $I_D = -4.6$ A		0.037	0.045	
		$V_{GS} = -1.8$ V, $I_D = -4.3$ A		0.046	0.056	
		$V_{GS} = -1.5$ V, $I_D = -1.3$ A		0.057	0.077	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -4$ V, $I_D = -5.1$ A		18		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -4$ V, $V_{GS} = 0$ V, $f = 1$ MHz		1290		pF
Output Capacitance	C_{oss}		420			
Reverse Transfer Capacitance	C_{rss}		270			
Total Gate Charge	Q_g	$V_{DS} = -4$ V, $V_{GS} = -8$ V, $I_D = -6$ A		23	35	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = -4$ V, $V_{GS} = -4.5$ V, $I_D = -6$ A		14	21	
Gate-Drain Charge	Q_{gd}		1.7			
Gate Resistance	R_g		$f = 1$ MHz	8		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -4$ V, $R_L = 0.7$ Ω $I_D \cong -5.6$ A, $V_{GEN} = -4.5$ V, $R_g = 1$ Ω		10	15	ns
Rise Time	t_r		70	110		
Turn-Off Delay Time	$t_{d(off)}$		60	90		
Fall Time	t_f		30	45		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -4$ V, $R_L = 0.7$ Ω $I_D \cong -5.6$ A, $V_{GEN} = -8$ V, $R_g = 1$ Ω		8	15	
Rise Time	t_r		70	110		
Turn-Off Delay Time	$t_{d(off)}$		55	85		
Fall Time	t_f		55	85		



SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$			- 6	A
Pulse Diode Forward Current	I_{SM}				- 25	
Body Diode Voltage	V_{SD}	$I_S = - 2.1\text{ A}$, $V_{GS} = 0\text{ V}$		- 0.7	- 1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = - 5.6\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $T_J = 25\text{ }^\circ\text{C}$		45	70	ns
Body Diode Reverse Recovery Charge	Q_{rr}			18	27	nC
Reverse Recovery Fall Time	t_a			18		ns
Reverse Recovery Rise Time	t_b			17		

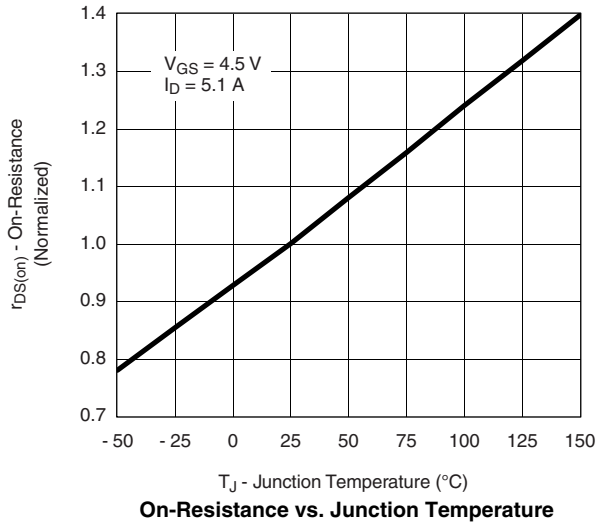
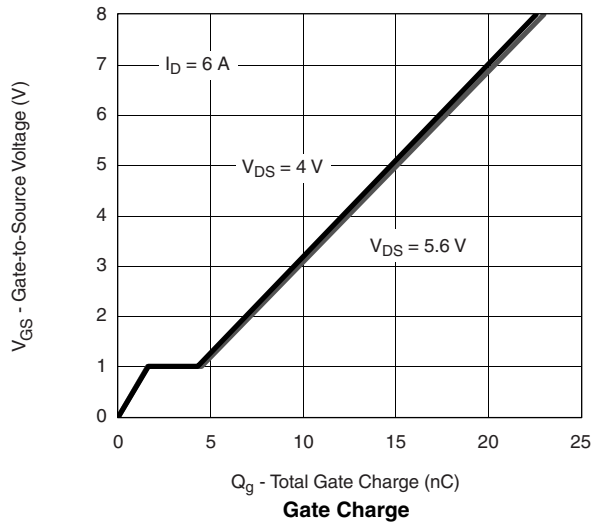
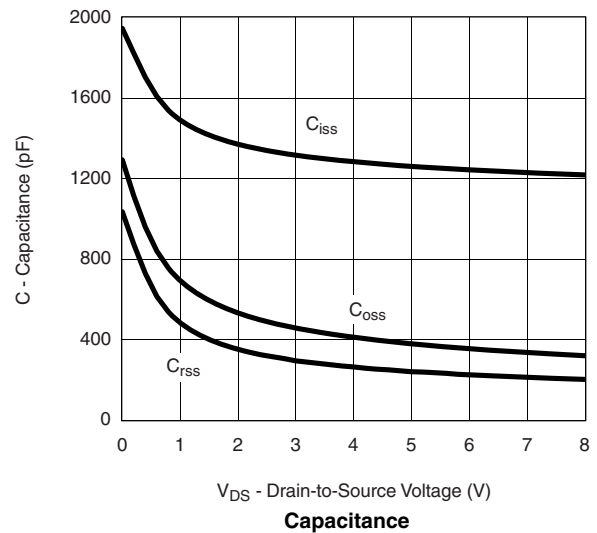
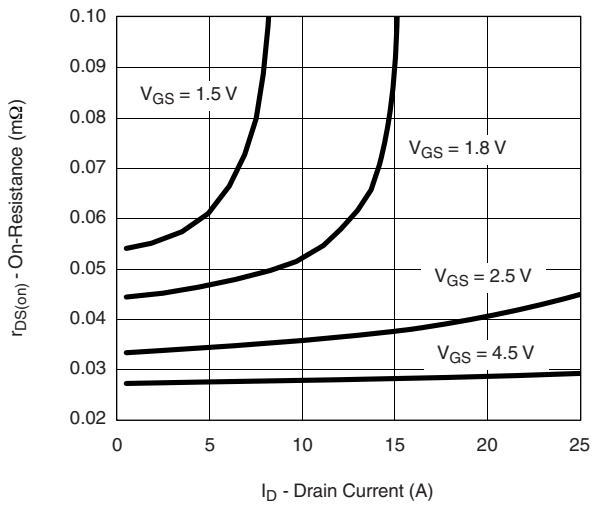
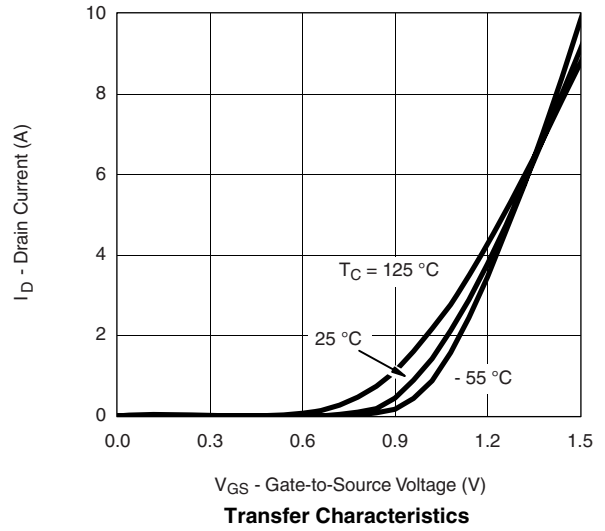
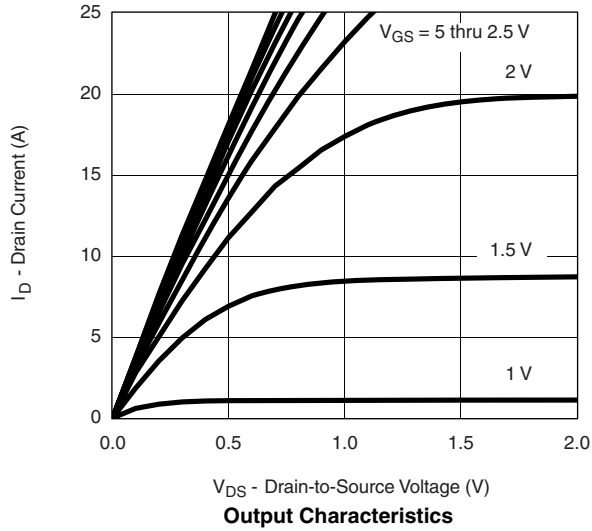
Notes:

- Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
- Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

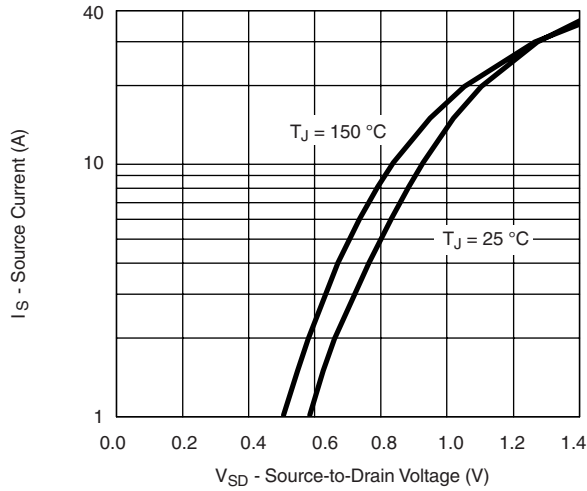


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

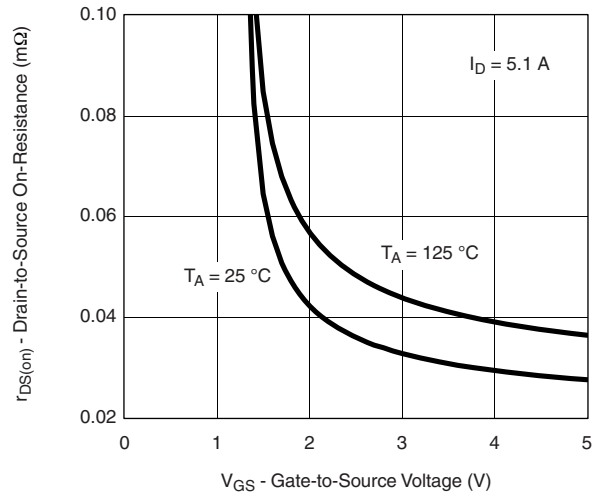




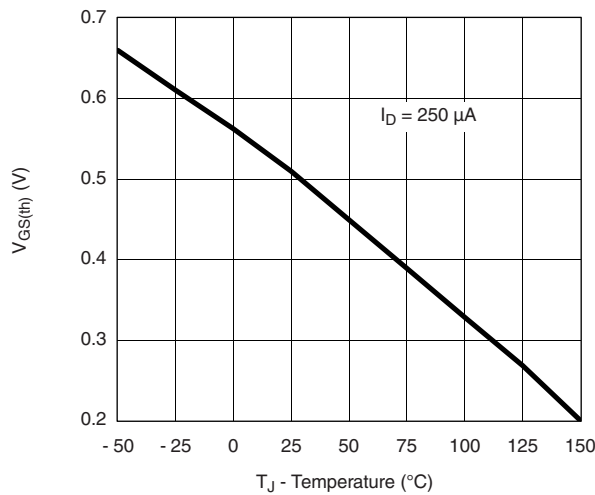
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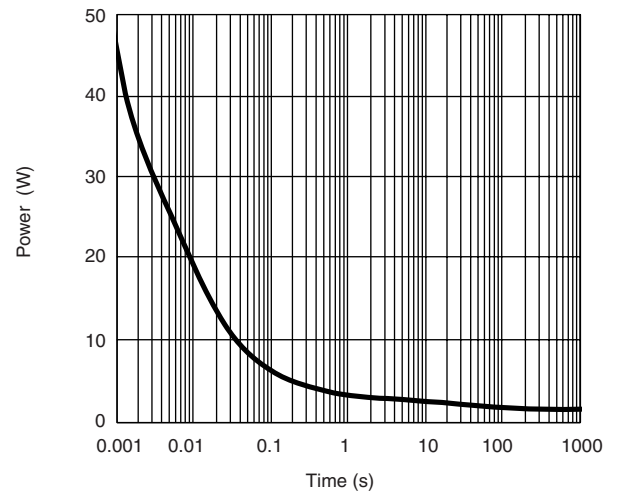
Source-Drain Diode Forward Voltage



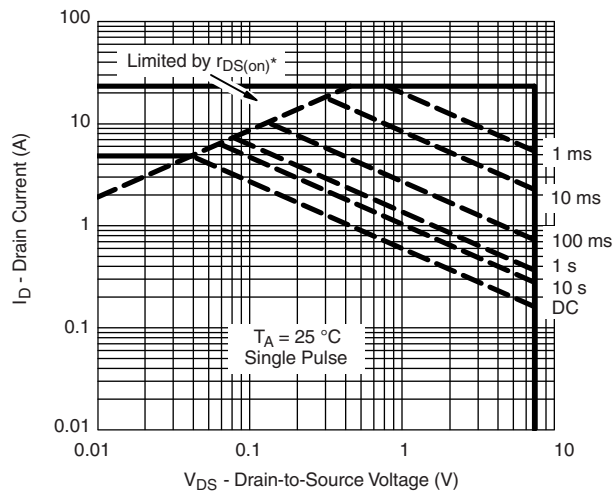
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage



Single Pulse Power, Junction-to-Ambient

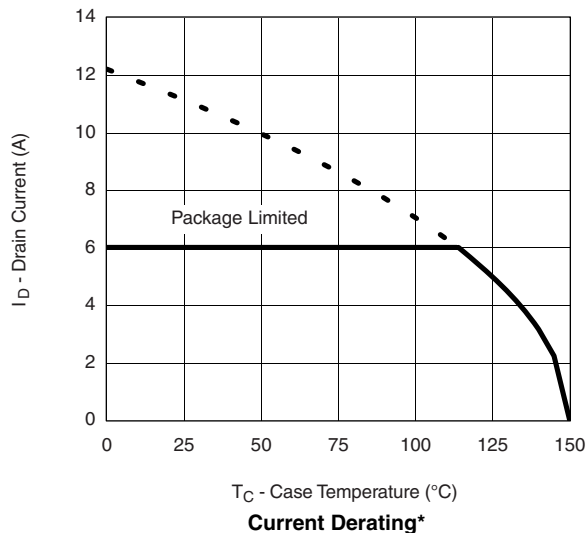


* $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient



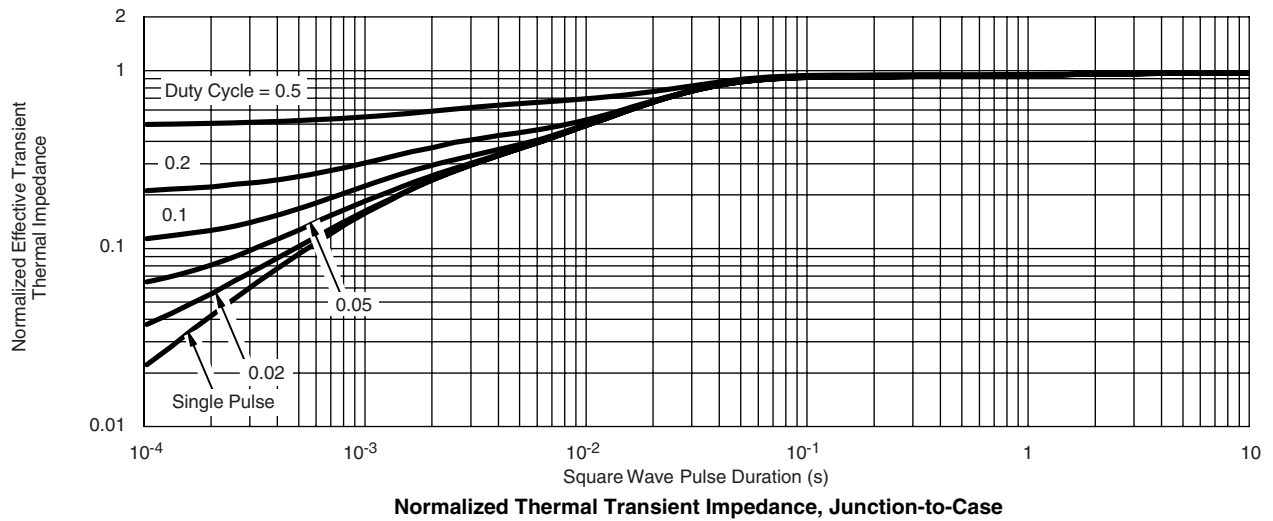
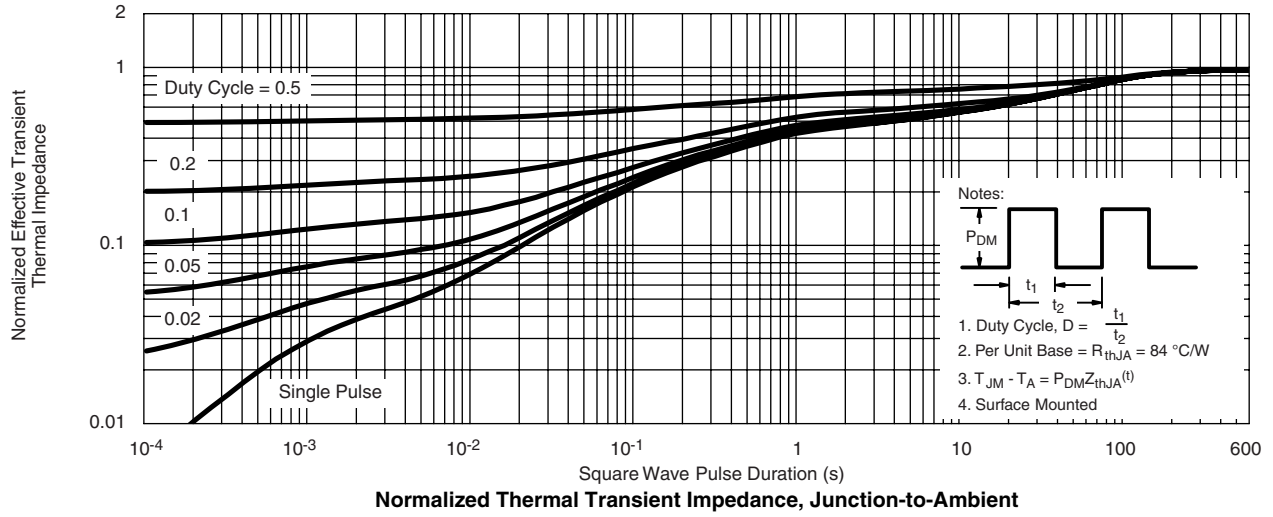
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)} = 150\text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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